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09/847479

CLASS	SUBCLASS	ISSUE CLASSIFICATION

PATENT NUMBER

BEST AVAILABLE

U.S. UTILITY Patent Application

O.I.P.E.	PATENT DATE
Q2 SCANNED NS4 QA SW	

APPLICATION NO.	CONT/PRIOR	CLASS	SUBCLASS	ART UNIT	EXAMINER
09/847479		430	311	1756	Barreca

APPLICANTS

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TITLE

Gate linewidth tailoring and critical dimension control for sub-100 nm devices using plasma etching

PTO-2040
12/99

ISSUING CLASSIFICATION

Continued on future Silo Impact File jackets

TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
<input type="checkbox"/> The term of this patent subsequent to _____ (date) has been disclaimed.				NOTICE OF ALLOWANCE MAILED	
<input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S Patent. No. _____ _____ _____				ISSUE FEE	
<input type="checkbox"/> The terminal _____ months of this patent have been disclaimed.				Amount Due	Date Paid
				ISSUE BATCH NUMBER	
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